

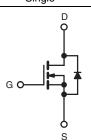
Vishay Siliconix

COMPLIANT

Power MOSFET

PRODUCT SUMMARY			
V _{DS} (V)	200		
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = 10 V	1.5	
Q _g (Max.) (nC)	8.2		
Q _{gs} (nC)	1.8		
Q _{gd} (nC)	4.5		
Configuration	Single		





N-Channel MOSFET

FEATURES

- Dynamic dV/dt Rating
- · Repetitive Avalanche Rated
- For Automatic Insertion
- End Stackable
- · Fast Switching
- · Ease of Paralleling
- Simple Drive Requirements
- Lead (Pb)-free Available

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The 4 pin DIP package is a low cost machine-insertable case style which can be stacked in multiple combinations on standard 0.1" pin centers. The dual drain serves as a thermal link to the mounting surface for power dissipation levels up to 1 W.

ORDERING INFORMATION	
Package	HEXDIP
Lead (Pb)-free	IRFD210PbF
Lead (PD)-liee	SiHFD210-E3
SnPb	IRFD210
SHIFD	SiHFD210

ABSOLUTE MAXIMUM RATINGS T _C = 25 °C, unless otherwise noted					
PARAMETER			LIMIT	UNIT	
Drain-Source Voltage			200	V	
Gate-Source Voltage			± 20	v	
V at 10 V	T _C = 25 °C	-	0.60	А	
VGS at 10 V	T _C = 100 °C	'D	0.38		
ulsed Drain Current ^a			4.8		
Linear Derating Factor			0.0083	W/°C	
Single Pulse Avalanche Energy ^b			79	mJ	
Repetitive Avalanche Current ^a			0.60	Α	
Repetitive Avalanche Energy ^a			0.10	mJ	
T _C = 25 °C		P _D	1.0	W	
Peak Diode Recovery dV/dt ^c		dV/dt	5.0	V/ns	
Operating Junction and Storage Temperature Range			- 55 to + 150	00	
for	10 s		300 ^d	°C	
	V_{GS} at 10 V	$V_{GS} \text{ at } 10 \text{ V}$ $T_{C} = 25 \text{ °C}$ $T_{C} = 100 \text{ °C}$ $T_{C} = 25 \text{ °C}$	$\begin{tabular}{c ccccccccccccccccccccccccccccccccccc$	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. V_{DD} = 50 V, starting T_J = 25 °C, L = 82 mH, R_G = 25 Ω , I_{AS} = 1.2 A (see fig. 12).
- c. $I_{SD} \le 3.3$ A, $dI/dt \le 70$ A/ μ s, $V_{DD} \le V_{DS}$, $T_J \le 150$ °C.
- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply

IRFD210, SiHFD210

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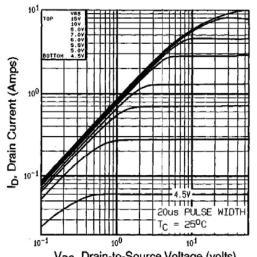
THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R_{thJA}	-	120	°C/W	

PARAMETER	SYMBOL	TES	MIN.	TYP.	MAX.	UNIT	
Static							
Drain-Source Breakdown Voltage	V _{DS}	V _{GS}	200	-	-	V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference to 25 °C, I _D = 1 mA		-	0.30	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$		-	4.0	V
Gate-Source Leakage	I _{GSS}	V _{GS} = ± 20 V		-	-	± 100	nA
Zone Ooks Walks are Basis Occurs		V _{DS} :	V _{DS} = 200 V, V _{GS} = 0 V		-	25	μΑ
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 160 \	V _{DS} = 160 V, V _{GS} = 0 V, T _J = 125 °C		-	250	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 0.36 A ^b	-	-	1.5	Ω
Forward Transconductance	9 _{fs}	V _{DS} =	= 50 V, I _D = 0.36 A ^b	0.10	-	-	S
Dynamic							
Input Capacitance	C_{iss}	V _{GS} = 0 V		-	140	-	pF
Output Capacitance	Coss		V _{DS} = 25 V		53	-	
Reverse Transfer Capacitance	C_{rss}	f = 1	0 MHz, see fig. 5	-	15	-	
Total Gate Charge	Q_g		$V_{GS} = 10 \text{ V}$ $I_D = 3.3 \text{ A}, V_{DS} = 160 \text{ V}$ see fig. 6 and 13^b	-	-	8.2	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V		-	-	1.8	
Gate-Drain Charge	Q_{gd}			-	-	4.5	
Turn-On Delay Time	t _{d(on)}		'		8.2	-	- ns
Rise Time	t _r	V_{DD} = 100 V, I_D = 3.3 A R_G = 24 Ω , R_D = 30 Ω , see fig. 10 ^b		-	17	-	
Turn-Off Delay Time	t _{d(off)}			-	14	-	
Fall Time	t _f			-	8.9	-	
Internal Drain Inductance	L_D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.0	-	ml l
Internal Source Inductance	L _S			-	6.0	-	- nH
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	0.60	А
Pulsed Diode Forward Current ^a	I _{SM}			-	-	4.8	
Body Diode Voltage	V _{SD}	$T_J = 25 ^{\circ}\text{C}, \ I_S = 0.60 \text{A}, \ V_{GS} = 0 \text{V}^{\text{b}}$		-	-	2.0	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 3.3 A, dl/dt = 100 A/μs ^b		-	150	310	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	0.60	1.4	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is do			ninated by	L _S and I	_D)

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11) b. Pulse width \leq 300 μs ; duty cycle \leq 2 %



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



 V_{DS} , Drain-to-Source Voltage (volts) Fig. 1 - Typical Output Characteristics, T_C = 25 °C

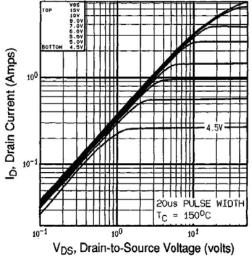


Fig. 2 - Typical Output Characteristics, $T_C = 150$ °C

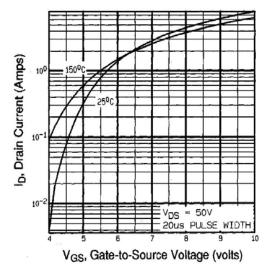


Fig. 3 - Typical Transfer Characteristics

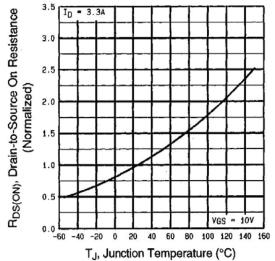


Fig. 4 - Normalized On-Resistance vs. Temperature

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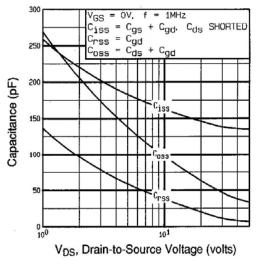


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

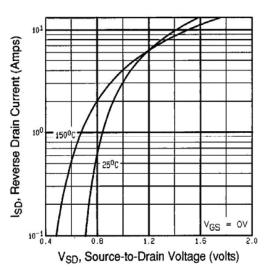


Fig. 7 - Typical Source-Drain Diode Forward Voltage

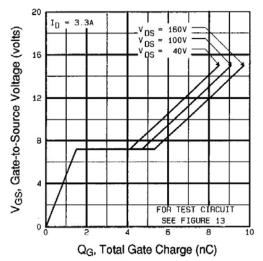


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

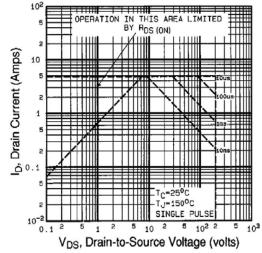


Fig. 8 - Maximum Safe Operating Area





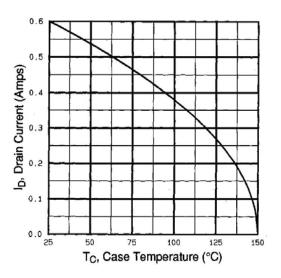


Fig. 9 - Maximum Drain Current vs. Case Temperature

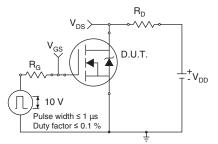


Fig. 10a - Switching Time Test Circuit

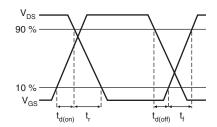


Fig. 10b - Switching Time Waveforms

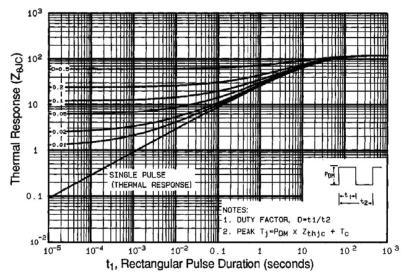


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

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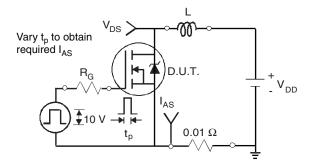


Fig. 12a - Unclamped Inductive Test Circuit

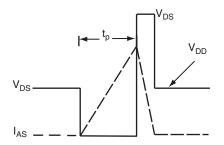


Fig. 12b - Unclamped Inductive Waveforms

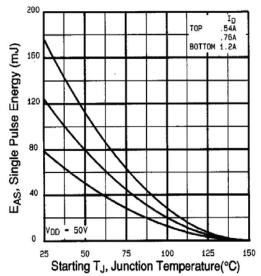


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

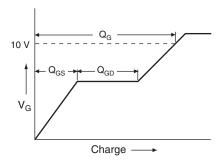


Fig. 13a - Basic Gate Charge Waveform

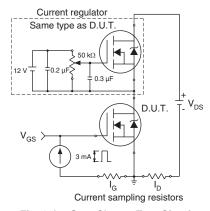
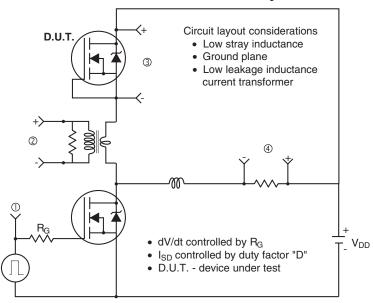
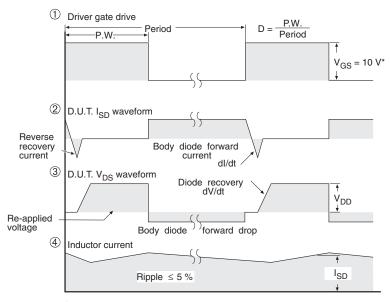


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit





* V_{GS} = 5 V for logic level devices and 3 V drive devices

Fig. 14 - For N-Channel

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Revision: 18-Jul-08

Document Number: 91000 www.vishay.com